## 1. General description

NPN low  $V_{CEsat}$  Breakthrough in a Small Signal (BISS) transistor, encapsulated in an ultra thin DFN2020D-3 (SOT1061D) leadless small Surface-Mounted Device (SMD) plastic package with medium power capability and visible and soldarable side pads.

PNP complement: PBSS5360PAS

### 2. Features and benefits

- Low collector-emitter saturation voltage V<sub>CEsat</sub>
- High collector current capability I<sub>C</sub> and I<sub>CM</sub>
- High collector current gain (h<sub>FE</sub>) at high I<sub>C</sub>
- High efficiency due to less heat generation
- High temperature applications up to 175 °C
- Reduced Printed-Circuit Board (PCB) area requirements
- Leadless small SMD plastic package with soldarable side pads
- Exposed heat sink for excellent thermal and electrical conductivity
- Suitable for Automatic Optical Inspection (AOI) of solder joint
- AEC-Q101 qualified

## 3. Applications

- Loadswitch
- Battery-driven devices
- Power management
- Charging circuits
- Power switches (e.g. motors, fans)

### 4. Quick reference data

Table 1. Quick reference data

| Symbol             | Parameter                               | Conditions                                                                                | Min | Тур | Max | Unit |
|--------------------|-----------------------------------------|-------------------------------------------------------------------------------------------|-----|-----|-----|------|
| V <sub>CEO</sub>   | collector-emitter voltage               | open base                                                                                 | -   | -   | 60  | V    |
| I <sub>C</sub>     | collector current                       |                                                                                           | -   | -   | 3   | Α    |
| I <sub>CM</sub>    | peak collector current                  | single pulse; t <sub>p</sub> ≤ 1 ms                                                       | -   | -   | 6   | Α    |
| R <sub>CEsat</sub> | collector-emitter saturation resistance | $I_C$ = 3 A; $I_B$ = 300 mA; pulsed;<br>$t_p \le$ 300 μs; $δ \le$ 0.02; $T_{amb}$ = 25 °C | -   | 73  | 108 | mΩ   |





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# 5. Pinning information

Table 2. Pinning information

| Pin | Symbol | Description | Simplified outline                          | Graphic symbol |
|-----|--------|-------------|---------------------------------------------|----------------|
| 1   | В      | base        | 3                                           | 3              |
| 2   | E      | emitter     |                                             | 1—             |
| 3   | С      | collector   | Transparent top view  DFN2020D-3 (SOT1061D) | 2<br>sym021    |

# 6. Ordering information

Table 3. Ordering information

| Type number | Package    |                                                                                                                    |          |  |  |
|-------------|------------|--------------------------------------------------------------------------------------------------------------------|----------|--|--|
|             | Name       | Description                                                                                                        | Version  |  |  |
| PBSS4360PAS | DFN2020D-3 | DFN2020D-3: plastic thermal enhanced ultra thin small outline package; no leads; 3 terminals; body 2 x 2 x 0.65 mm | SOT1061D |  |  |

# 7. Marking

Table 4. Marking codes

| Type number | Marking code |
|-------------|--------------|
| PBSS4360PAS | E9           |

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## 8. Limiting values

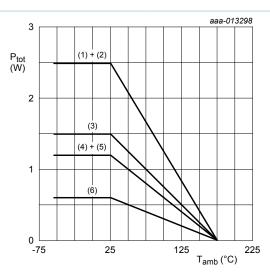
Table 5. Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134).

| Symbol           | Parameter                 | Conditions                          |        | Min | Max | Unit |
|------------------|---------------------------|-------------------------------------|--------|-----|-----|------|
| $V_{CBO}$        | collector-base voltage    | open emitter                        |        | -   | 80  | V    |
| $V_{CEO}$        | collector-emitter voltage | open base                           |        | -   | 60  | V    |
| V <sub>EBO</sub> | emitter-base voltage      | open collector                      |        | -   | 7   | V    |
| I <sub>C</sub>   | collector current         |                                     |        | -   | 3   | Α    |
| I <sub>CM</sub>  | peak collector current    | single pulse; t <sub>p</sub> ≤ 1 ms |        | -   | 6   | Α    |
| I <sub>B</sub>   | base current              |                                     |        | -   | 500 | mA   |
| I <sub>BM</sub>  | peak base current         |                                     |        | -   | 1   | Α    |
| P <sub>tot</sub> | total power dissipation   | T <sub>amb</sub> ≤ 25 °C            | [1]    | -   | 0.6 | W    |
|                  |                           |                                     | [2][3] | -   | 1.2 | W    |
|                  |                           |                                     | [4]    | -   | 1.5 | W    |
|                  |                           |                                     | [5][6] | -   | 2.5 | W    |
| Tj               | junction temperature      |                                     |        | -   | 175 | °C   |
| T <sub>amb</sub> | ambient temperature       |                                     |        | -55 | 175 | °C   |
| T <sub>stg</sub> | storage temperature       |                                     |        | -65 | 175 | °C   |

- [1] Device mounted on an FR4 Printed-Circuit Board (PCB), single-sided copper, tin-plated and standard footprint.
- [2] Device mounted on an FR4 PCB, single-sided copper, tin-plated, mounting pad for collector 1 cm<sup>2</sup>.
- [3] Device mounted on an FR4 PCB, 4-layer copper, tin-plated and standard footprint.
- Device mounted on an FR4 PCB, single-sided copper, tin-plated, mounting pad for collector 6 cm<sup>2</sup>.
- [5] Device mounted on a ceramic PCB, Al<sub>2</sub>O<sub>3</sub>, standard footprint.
- [6] Device mounted on an FR4 PCB, 4-layer copper, tin-plated and mounting pad for collector 1 cm<sup>2</sup>.

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- (1) Ceramic PCB, single-sided copper, standard footprint
- (2) FR4 PCB, 4-layer copper, 1 cm<sup>2</sup>
- (3) FR4 PCB, single-sided copper, 6 cm<sup>2</sup>
- (4) FR4 PCB, single-sided copper, 1 cm<sup>2</sup>
- (5) FR4 PCB, 4-layer copper, standard footprint
- (6) FR4 PCB, single-sided copper, standard footprint

Fig. 1. Power derating curves

### 9. Thermal characteristics

Table 6. Thermal characteristics

| Symbol                                                           | Parameter | Conditions |        | Min | Тур | Max | Unit |
|------------------------------------------------------------------|-----------|------------|--------|-----|-----|-----|------|
| R <sub>th(j-a)</sub> thermal resistance from junction to ambient |           |            | [1]    | -   | -   | 250 | K/W  |
|                                                                  | 1         |            | [2][3] | -   | -   | 125 | K/W  |
|                                                                  | ambient   |            | [4]    | -   | -   | 100 | K/W  |
|                                                                  |           |            | [5][6] | -   | -   | 60  | K/W  |

- [1] Device mounted on an FR4 PCB, single-sided copper, tin-plated and standard footprint.
- Device mounted on an FR4 PCB, single-sided copper, tin-plated, mounting pad for collector 1 cm<sup>2</sup>.
- [3] Device mounted on an FR4 PCB, 4-layer copper, tin-plated and standard footprint.
- [4] Device mounted on an FR4 PCB, single-sided copper, tin-plated, mounting pad for collector 6 cm<sup>2</sup>.
- [5] Device mounted on a ceramic PCB, Al<sub>2</sub>O<sub>3</sub>, standard footprint.
- [6] Device mounted on a FR4 PCB, 4-layer copper, tin-plated and mounting pad for collector 1 cm<sup>2</sup>.

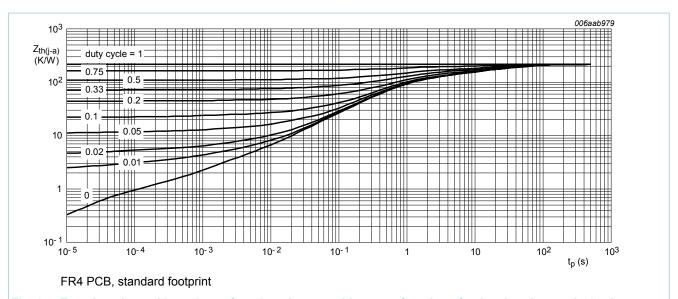


Fig. 2. Transient thermal impedance from junction to ambient as a function of pulse duration; typical values

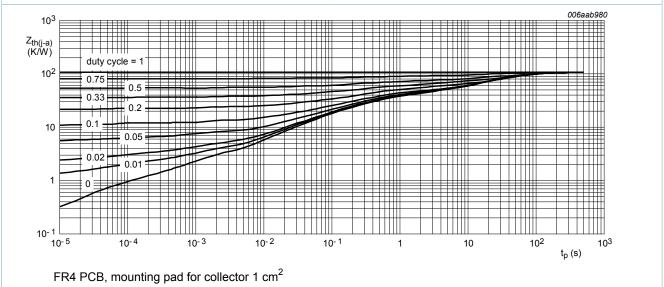


Fig. 3. Transient thermal impedance from junction to ambient as a function of pulse duration; typical values

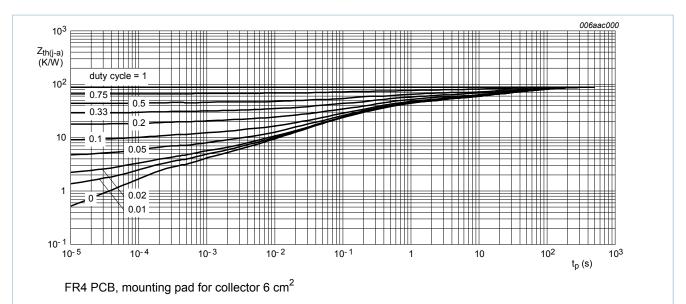


Fig. 4. Transient thermal impedance from junction to ambient as a function of pulse duration; typical values

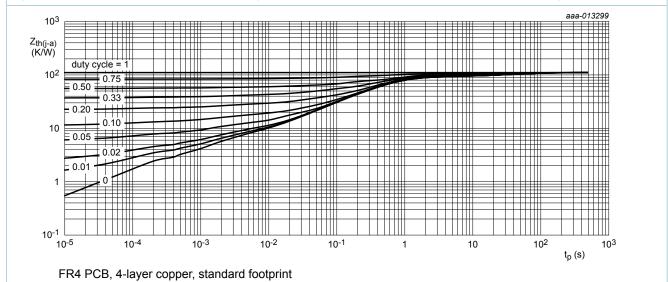
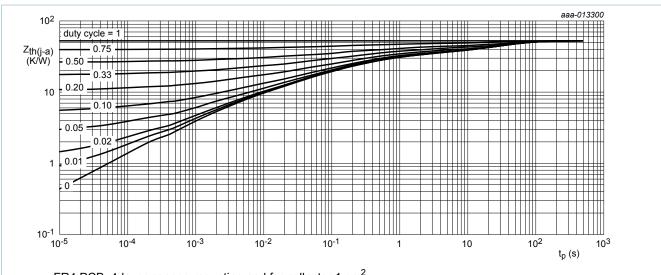
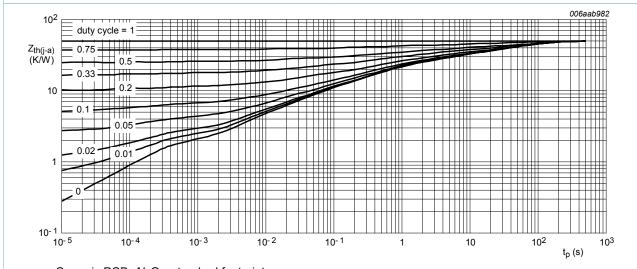


Fig. 5. Transient thermal impedance from junction to ambient as a function of pulse duration; typical values



FR4 PCB, 4-layer copper, mounting pad for collector 1 cm<sup>2</sup>

Fig. 6. Transient thermal impedance from junction to ambient as a function of pulse duration; typical values



Ceramic PCB, Al<sub>2</sub>O<sub>3</sub>, standard footprint

Fig. 7. Transient thermal impedance from junction to ambient as a function of pulse duration; typical values

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## 10. Characteristics

Table 7. Characteristics

| Symbol             | Parameter                               | Conditions                                                                                                                                          | Min | Тур  | Max  | Unit |
|--------------------|-----------------------------------------|-----------------------------------------------------------------------------------------------------------------------------------------------------|-----|------|------|------|
| I <sub>CBO</sub>   | collector-base cut-off                  | V <sub>CB</sub> = 64 V; I <sub>E</sub> = 0 A; T <sub>amb</sub> = 25 °C                                                                              | -   | -    | 100  | nA   |
| current            |                                         | V <sub>CB</sub> = 64 V; I <sub>E</sub> = 0 A; T <sub>j</sub> = 150 °C                                                                               | -   | -    | 50   | μΑ   |
| I <sub>CES</sub>   | collector-emitter cut-off current       | V <sub>CE</sub> = 48 V; V <sub>BE</sub> = 0 V; T <sub>amb</sub> = 25 °C                                                                             | -   | -    | 100  | nA   |
| I <sub>EBO</sub>   | emitter-base cut-off current            | $V_{EB} = 5.6 \text{ V}; I_{C} = 0 \text{ A}; T_{amb} = 25 \text{ °C}$                                                                              | -   | -    | 100  | nA   |
| h <sub>FE</sub>    | DC current gain                         | $V_{CE} = 5 \text{ V; } I_{C} = 0.05 \text{ A; pulsed;}$<br>$t_{p} \le 300  \mu\text{s; } \delta \le 0.02 \text{ ; } T_{amb} = 25 ^{\circ}\text{C}$ | 200 | 380  | -    |      |
|                    |                                         | $V_{CE} = 5 \text{ V}; I_{C} = 0.5 \text{ A}; \text{ pulsed};$<br>$t_{p} \le 300  \mu\text{s}; \delta \le 0.02 ; T_{amb} = 25 ^{\circ}\text{C}$     | 200 | 360  | -    |      |
|                    |                                         | $V_{CE}$ = 5 V; $I_{C}$ = 1 A; pulsed; $t_{p}$ ≤ 300 μs; $\delta$ ≤ 0.02 ; $T_{amb}$ = 25 °C                                                        | 200 | 330  | -    |      |
|                    |                                         | $V_{CE}$ = 5 V; $I_{C}$ = 2 A; pulsed; $t_{p}$ ≤ 300 μs; $\delta$ ≤ 0.02 ; $T_{amb}$ = 25 °C                                                        | 125 | 220  | -    |      |
|                    |                                         | $V_{CE} = 5 \text{ V; } I_{C} = 3 \text{ A; } t_{p} \le 300  \mu\text{s;}$<br>$\delta \le 0.02; T_{amb} = 25 \text{ °C}$                            | 75  | 140  | -    |      |
| V <sub>CEsat</sub> | collector-emitter saturation voltage    | $I_{C}$ = 0.5 A; $I_{B}$ = 50 mA; pulsed;<br>$t_{p} \le 300 \ \mu s; \ \delta \le 0.02; \ T_{amb}$ = 25 °C                                          | -   | 45   | 60   | mV   |
|                    |                                         | $I_{C}$ = 1 A; $I_{B}$ = 100 mA; pulsed;<br>$t_{p} \le 300 \text{ µs}; \delta \le 0.02; T_{amb} = 25 ^{\circ}C$                                     | -   | 80   | 110  | mV   |
|                    |                                         | $I_C$ = 2 A; $I_B$ = 200 mA; pulsed;<br>$t_p \le 300 \text{ μs}; \delta \le 0.02; T_{amb} = 25 \text{ °C}$                                          | -   | 150  | 210  | mV   |
|                    |                                         | I <sub>C</sub> = 3 A; I <sub>B</sub> = 300 mA; pulsed;                                                                                              | -   | 220  | 325  | mV   |
| R <sub>CEsat</sub> | collector-emitter saturation resistance | $t_p \le 300 \text{ μs; } δ \le 0.02; T_{amb} = 25 \text{ °C}$                                                                                      | -   | 73   | 108  | mΩ   |
| $V_{BEsat}$        | base-emitter saturation voltage         | $I_{C}$ = 2 A; $I_{B}$ = 100 mA; pulsed;<br>$t_{p} \le 300 \ \mu s; \ \delta \le 0.02; \ T_{amb}$ = 25 °C                                           | -   | 0.9  | 1.1  | V    |
| $V_{BEon}$         | base-emitter turn-on voltage            | $V_{CE}$ = 5 V; $I_{C}$ = 1 A; pulsed; $t_{p}$ ≤ 300 μs; $\delta$ ≤ 0.02; $T_{amb}$ = 25 °C                                                         | -   | 0.75 | 0.95 | V    |
| t <sub>d</sub>     | delay time                              | I <sub>C</sub> = 2 A; I <sub>Bon</sub> = 0.1 A; I <sub>Boff</sub> = -0.1 A;                                                                         | -   | 11   | -    | ns   |
| t <sub>r</sub>     | rise time                               | T <sub>amb</sub> = 25 °C                                                                                                                            | -   | 130  | -    | ns   |
| t <sub>on</sub>    | turn-on time                            |                                                                                                                                                     | -   | 141  | -    | ns   |
| ts                 | storage time                            |                                                                                                                                                     | -   | 200  | -    | ns   |
| t <sub>f</sub>     | fall time                               |                                                                                                                                                     | -   | 110  | -    | ns   |
| t <sub>off</sub>   | turn-off time                           |                                                                                                                                                     | -   | 310  | -    | ns   |

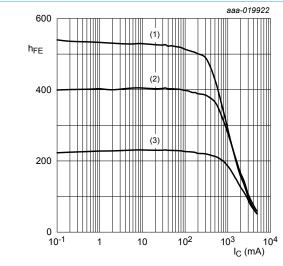
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### 60 V, 3 A NPN low VCEsat (BISS) transistor

| Symbol         | Parameter             | Conditions                                                                                                 | Min | Тур | Max | Unit |
|----------------|-----------------------|------------------------------------------------------------------------------------------------------------|-----|-----|-----|------|
| f <sub>T</sub> | transition frequency  | $V_{CE}$ = 10 V; $I_{C}$ = 100 mA; f = 100 MHz;<br>$T_{amb}$ = 25 °C                                       | 75  | 160 | -   | MHz  |
| C <sub>c</sub> | collector capacitance | V <sub>CB</sub> = 10 V; I <sub>E</sub> = 0 A; i <sub>e</sub> = 0 A;<br>f = 1 MHz; T <sub>amb</sub> = 25 °C | -   | 11  | 14  | pF   |



 $V_{CE} = 2 V$ 

(1)  $T_{amb} = 100 \, ^{\circ}C$ 

(2)  $T_{amb} = 25 \, ^{\circ}C$ 

(3)  $T_{amb} = -55 \,^{\circ}C$ 

Fig. 8. DC current gain as a function of collector current; typical values

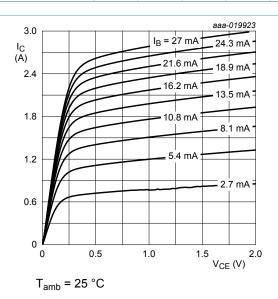
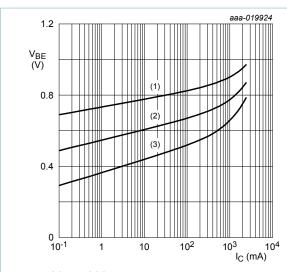


Fig. 9. Collector current as a function of collectoremitter voltage; typical values



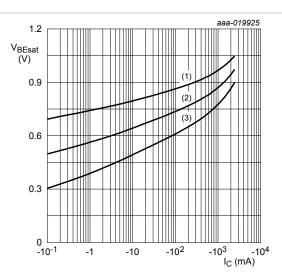
$$V_{CE} = 2 V$$

(1) 
$$T_{amb} = -55 \, ^{\circ}C$$

(2) 
$$T_{amb}$$
 = 25 °C

(3) 
$$T_{amb}$$
 = 100 °C

Fig. 10. Base-emitter voltage as a function of collector current; typical values



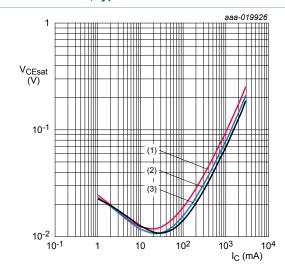
$$I_{\rm C}/I_{\rm B} = 20$$

(1) 
$$T_{amb} = -55 \, ^{\circ}C$$

(2) 
$$T_{amb} = 25 \, ^{\circ}C$$

(3) 
$$T_{amb} = 100 \, ^{\circ}C$$

Fig. 11. Base-emitter saturation voltage as a function of collector current; typical values



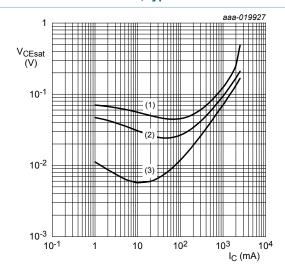
$$I_{\rm C}/I_{\rm B} = 20$$

(1) 
$$T_{amb} = 100 \, ^{\circ}C$$

(2) 
$$T_{amb}$$
 = 25 °C

(3) 
$$T_{amb} = -55 \, ^{\circ}C$$

Fig. 12. Collector-emitter saturation voltage as a function of collector current; typical values

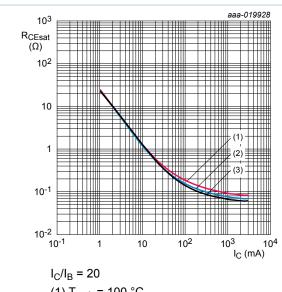


(1) 
$$I_C/I_B = 100$$

(2) 
$$I_C/I_B = 50$$

(3) 
$$I_C/I_B = 10$$

Fig. 13. Collector-emitter saturation voltage as a function of collector current; typical values

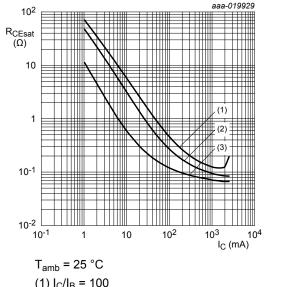


(1) 
$$T_{amb} = 100 \, ^{\circ}C$$

(2) 
$$T_{amb}$$
 = 25 °C

(3) 
$$T_{amb} = -55 \, ^{\circ}C$$

Fig. 14. Collector-emitter saturation resistance as a function of collector current; typical values



(1)  $I_C/I_B = 100$ 

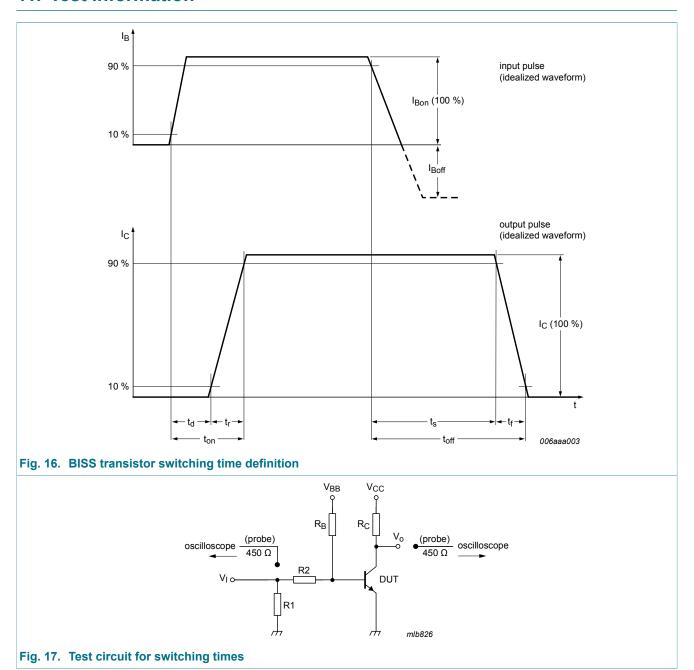
(2) 
$$I_C/I_B = 50$$

(3) 
$$I_C/I_B = 10$$

Fig. 15. Collector-emitter saturation resistance as a function of collector current; typical values

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### 11. Test information

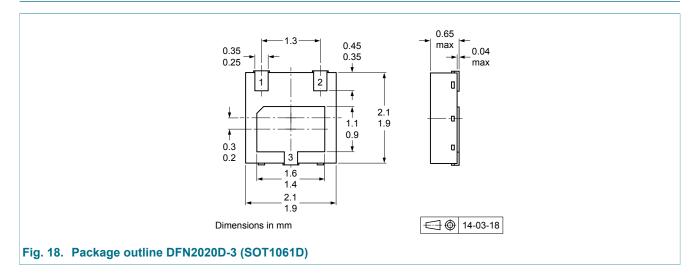


### 11.1 Quality information

This product has been qualified in accordance with the Automotive Electronics Council (AEC) standard *Q101 - Stress test qualification for discrete semiconductors*, and is suitable for use in automotive applications.

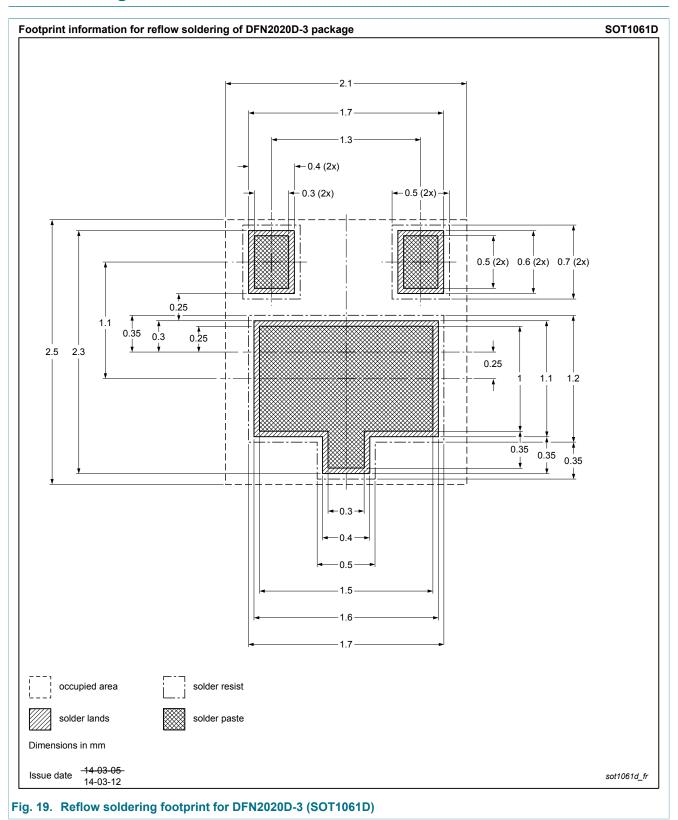
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## 12. Package outline



60 V, 3 A NPN low VCEsat (BISS) transistor

## 13. Soldering



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# 14. Revision history

### Table 8. Revision history

| Data sheet ID   | Release date | Data sheet status  | Change notice | Supersedes |
|-----------------|--------------|--------------------|---------------|------------|
| PBSS4360PAS v.1 | 20151016     | Product data sheet | -             | -          |

### 60 V, 3 A NPN low VCEsat (BISS) transistor

### 15. Legal information

### 15.1 Data sheet status

| Document status [1][2]               | Product status [3] | Definition                                                                            |
|--------------------------------------|--------------------|---------------------------------------------------------------------------------------|
| Objective<br>[short] data<br>sheet   | Development        | This document contains data from the objective specification for product development. |
| Preliminary<br>[short] data<br>sheet | Qualification      | This document contains data from the preliminary specification.                       |
| Product<br>[short] data<br>sheet     | Production         | This document contains the product specification.                                     |

- Please consult the most recently issued document before initiating or completing a design.
- [2] The term 'short data sheet' is explained in section "Definitions".
- The product status of device(s) described in this document may have changed since this document was published and may differ in case of multiple devices. The latest product status information is available on the Internet at URL <a href="http://www.nxp.com">http://www.nxp.com</a>.

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**NXP Semiconductors** 

## PBSS4360PAS

### 60 V, 3 A NPN low VCEsat (BISS) transistor

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